	Type	L #	Hits	Search Text	DBs	Time Stamp
1	BRS	L1	6993	mask$3 and pattern$1 and correct$3 and wafer$1 and project$3 and optical$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 18:16
2	BRS	L2	252	1 and design adj pattern	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 18:16
3	BRS	L3	180	2 and (edge$1 or contour or boundary or border)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 18:17
4	BRS	L4	81	3 and extract$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 18:17
5	BRS	L5	61	4 and length	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 18:18

	Type	L #	Hits	Search Text	DBs	Time Stamp
6	BRS	L6	31	5 and (correlat$4 or match$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 18:18
7	BRS	L7	29	6 and distance	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 18:19
8	BRS	L8	23	7 and (one adj dimenstion$4 or two adj dimension$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 18:21
9	BRS	L9	20	8 and mov$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 18:21
10	BRS	L10	19	9 and width	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 18:21

	Type	L #	Hits	Search Text	DBs	Time Stamp
11	BRS	L11	3	10 and (critical or threshold) near2 (distance or length)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 18:23